14th ANNUAL FIB SEM MEETING SCHEDULE

WEDNESDAY MAY 4TH

ThermoFisher SCIENTIFIC

8:30 – 9:30 EDT	Check-in + Breakfast
9:30 – 9:35	Welcome + Housekeeping
9:35 – 10:20	Invited Tutorial: The History of FIB Applications: From Novelty to Necessity
	Lucille Giannuzzi EXpressLO LLC
	<u>Abstract + Bio</u>
10:20 – 10:50	Invited: (on-line) Multi-Method Characterization Workflow for Advanced Si-based Anodes
	Roland Brunner Materials Center Leoben
	Abstract
10:50 – 11:20	Coffee Break
11:20 – 11:50	Invited: FIB preparation of low melting point metals
	Joe Michael Independent Consultant
	Abstract
11:50 – 12:05	Strategies for 3D FIB Tomography Data Acquisition to Enable Accurate Materials Modelling and Simulation
	Stephen Kelly Carl Zeiss Research Microscopy Solutions
	Abstract
12:05 – 12:20	Advanced 2D and 3D Characterization of Fiber Optic Nanoparticles using SEM/FIB/TEM
	Rick Passey Thermo Fisher Scientific
	<u>Abstract</u>
12:20 – 12:35	A Stack Alignment Toolbox for Serial Electron Microscopy
	Alex Hall Thermo Fisher Scientific
	Abstract



























14th ANNUAL FIB SEM MEETING SCHEDULE

WEDNESDAY MAY 4TH

Thermo Fisher SCIENTIFIC

12:35 – 13:30 ED	DT Lunch
13:30 – 14:00	Invited: (on-line) Ion Microscopy, Machining, and Elemental Analysis with the Cesium Low Temperature Ion Source (LoTIS)
	Adam Steele zeroK NanoTech
	<u>Abstract</u>
14:00 – 14:15	Novel FIB-nanofabrication strategies with Lithium and Bismuth ions from GaBiLi Liquid Metal Alloy Ion Sources
	Yang Yu Raith
	Abstract
14:15 – 14:30	Cryo-FIB/SEM for Micro-scale Analysis of Solid-state Li-Ion Battery Electrolytes
	Fred Meisenkothen <i>NIST</i>
	Abstract
14:30 – 14:45	EDS and EBSD Study of Battery Shell
	Jiancun Rao University of Maryland
	Abstract
14:45 – 15:00	Investigating Early HCoV-229E Virus Mediated Endocytosis Nanoscale Interactions with Focused Ion Beam Scanning Electron Microscopy
	Alyssa Williams McMaster University / FIBICS
	Abstract
15:00 – 15:30	Coffee Break
15:30 – 16:00	Invited: So You Bought a Cryo-Plasma FIB with ToF-SIMS. Now What?
	Jamie Ford University of Pennsylvania
	<u>Abstract</u>





























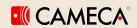
14th ANNUAL FIB SEM MEETING SCHEDULE

WEDNESDAY MAY 4TH

Thermo Fisher SCIENTIFIC

16:00 – 16:15 **EDT** Informing metallurgical issues related to additively manufacturing using FIB sample preparation for TKD and TEM analyses Andy lams NIST **Abstract** 16:15 - 16:30 DeepLearning Segmentation of BioSEM Samples is Robust and High Throughput Mike Marsh **ORS Abstract** 16:30 - 16:45 Imaging and understanding metal organic frameworks using advanced scanning electron microscopy techniques Maadhav Kothari Carl Zeiss Microscopy **Abstract** 16:45 - 17:00 Free 17:00 - 19:00 Happy Hour at the K-Center





























14th ANNUAL FIB SEM MEETING SCHEDULE

THURSDAY MAY 5TH

Thermo Fisher SCIENTIFIC

9:30 – 9:35 9:35 – 10:05	Welcome + Housekeeping Invited: (on-line) Solutions for Characterization of Semiconductors by Combining Plasma FIB Milling, Laser Ablation and Gas-Assisted Delayering Lukáš Hladík
9:35 – 10:05	Invited: (on-line) Solutions for Characterization of Semiconductors by Combining Plasma FIB Milling, Laser Ablation and Gas-Assisted Delayering
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	TESCAN ORSAY HOLDING a.s.
<u> </u>	<u>Abstract</u>
	(on-line) VirtualFIB: Simulating specimen orientation in FIB for advanced in situ lift-out
	Aleksander B. Mosberg SuperSTEM
4	<u>Abstract</u>
	<mark>(on-line)</mark> FIB-Induced Unique Self-Organization for 3D Nanostructures on Germanium Surface
	Bhaveshkumar Kamaliya IIT (India Institute of Technology)
	<u>Abstract</u>
10:45 – 11:00	Build your own open-source web viewer for 3D FIB-SEM data
	Joachim de Fourestier FIBICS / McMaster University
<u> </u>	<u>Abstract</u>
11:00 – 11:30	Coffee Break
r	Invited: More than Moore: How focused ion beam microscopy is meeting the demands of the semiconductor Industry
-	Adam Stokes Thermo Fisher Scientific
	<u>Abstract</u>
	Invited: FIB TEM Sample Preparation Artifacts in Semiconductors
	Lynne Gignac IBM
	<u>Abstract</u>





























14th ANNUAL FIB SEM MEETING SCHEDULE

THURSDAY MAY 5TH

ThermoFisher SCIENTIFIC

12:30 – 13:30 EDT	Lunch
13:30 – 14:00	Invited: 3D tomography on semiconductor samples for defect detection and metrology
	Thomas Korb Carl Zeiss SMT
	Abstract
14:00 – 14:15	Novel Use of EXLO for Cryo-Manipulation of FIB Specimens
	Lucille Giannuzzi EXpressLO LLC
	Abstract
14:15 – 14:30	(on-line) Correlative Raman spectroscopy and electron microscopy studies of Ga FIB and post-FIB Ar ion milling of Si TEM specimens
	Cecile Bonifacio E.A. Fischione Instruments, Inc.
	Abstract
14:30 – 14:45	TEM sample preparation of diverse materials
	Trevor Clark Pennsylvania State University
	Abstract
14:45 – 15:15	Coffee Break
15:15 – 16:00	Invited Tutorial: An Introduction to the FIB as a Microchip Circuit Edit Tool
	Steve Herschbein Independent Consultant
	Abstract + Bio
16:00	Adjourn















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